

Search Notes

Application/Control No.

10/052,870

Examiner

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Applicant(s)/Patent under
Reexamination

SHI ET AL.

Art Unit

26346

SEARCHED

Class	Subclass	Date	Examiner
375	219	6/15/2005	JP
	316	6/15/2005	JP
	324	6/15/2005	JP
	344	6/15/2005	JP
	345	6/15/2005	JP
	346	6/15/2005	JP
455	130	6/15/2005	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT USPGPUB EPO JPO	6/15/2005	JP
Inventor Name Search EAST/EDAN	6/15/2005	JP